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2879**U.S. PATENT DOCUMENTS**

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
	5,674,553	10/07/1997	Shinoda et al.	427	68	06/02/1995
	6,433,477 B1	08/13/2002	Ha et al.	313	586	10/22/1998

U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	
	JP 09-237580	09/09/1997	Japan (English Abstract and Japanese Full Text)			X	
	JP 10-228858	08/25/1998	Japan (English Abstract and Japanese Full Text)			X	
	JP 11-067099	03/09/1999	Japan (English Abstract and Japanese Full Text)			X	
	JP 10-283934	10/23/1998	Japan (English Abstract and Japanese Full Text)			X	
	JP 10-199427	07/31/1998	Japan (English Abstract and Japanese Full Text)			X	
	JP 10-308176	11/17/1998	Japan (English Abstract and Japanese Full Text)			X	
	JP 10-308177	11/17/1998	Japan (English Abstract and Japanese Full Text)			X	
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	JP 09-022656	01/21/1997	Japan (English Abstract and Japanese Full Text)			X	
	JP 09-129142	05/16/1997	Japan (English Abstract and Japanese Full Text)			X	
	JP 09-259768	10/03/1997	Japan (English Abstract and Japanese Full Text)			X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

EXAMINER	DATE CONSIDERED

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